

## CLAIMS:

1. An electronic circuit comprising:  
first and second combinational logic blocks; and  
a latch positioned between the combinational logic blocks;  
wherein the electronic circuit is adapted to operate in a normal mode in which  
5 the latch is opened and closed in response to an enable signal, and a test mode in which the  
latch is held open.
2. An electronic circuit as claimed in claim 1, further comprising a latch control  
circuit connected to the latch, the latch control circuit being adapted to control the latch with  
10 the enable signal when the electronic circuit is in the normal mode, and to hold the latch open  
when the electronic circuit is in the test mode.
3. An electronic circuit as claimed in claim 2, wherein the latch control circuit  
receives a signal indicating the mode of operation of the electronic circuit.  
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4. An electronic circuit as claimed in one of claims 1 to 3, further comprising  
means for inserting test data into the first combinational logic block when the electronic  
circuit is in the test mode; the test data being processed by the first and second combinational  
logic blocks as though they are a single combinational logic block.  
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5. An electronic circuit as claimed in claim 4, further comprising means for  
reading the processed test data from the second combinational logic block when the  
electronic circuit is in the test mode.
- 25 6. A method of operating an electronic circuit, the electronic circuit comprising  
first and second combinational logic blocks and a latch positioned between the blocks, the  
method comprising:  
operating the electronic circuit in a normal mode in which the latch is opened  
and closed in response to an enable signal, and a test mode in which the latch is held open.

7. A method as claimed in claim 6, further comprising the steps of:  
inserting test data into the first combinational logic block when the electronic circuit is in the test mode; and
- 5 retrieving processed test data from the second combinational logic block;  
wherein the test data is processed by the first and second combinational logic blocks as though they are a single combinational logic block.